

<b>Notice of References Cited</b>	Application/Control No. 10/767,477		Applicant(s)/Patent Under Reexamination CZAJKOWSKI, DAVID R.	
	Examiner Joshua A. Lohn		Art Unit 2114	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0055607	03-2005	Czajkowski et al.	714/025
*	B	US-2004/0153747	08-2004	Czajkowski, David	714/010
*	C	US-5,822,515	10-1998	Baylocq, Michel B.	714/56
*	D	US-5,706,423	01-1998	Sugimoto, Hideki	714/49
*	E	US-4,670,880	06-1987	Jitsukawa et al.	714/797
*	F	US-4,132,975	01-1979	Koike, Nobuhiko	714/797
*	G	US-4,817,094	03-1989	Lebizay et al.	714/797
*	H	US-4,943,969	07-1990	Criswell, Peter B.	714/820
*	I	US-4,959,836	09-1990	Berard et al.	714/822
*	J	US-5,235,220	08-1993	Takizawa, Hiroshi	326/35
*	K	US-6,910,178	06-2005	Kiselev et al.	714/819
*	L	US-6,625,756	09-2003	Grochowski et al.	714/17
*	M	US-6,298,289	10-2001	Lloyd et al.	701/13

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	GB 2 903 614				
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mukherjee et al.; "Detailed Design and Evaluation of Redundant Multithreading Alternatives"; International Conference on Computer Architecture, Proceedings of the 29 <sup>th</sup> Annual International Symposium on Computer Architecture; published 2002; pages 99-110
	V	Reinhardt et al.; "Transient Fault Detection Via Simultaneous Multithreading"; International Conference on Computer Architecture, Proceedings of the 27 <sup>th</sup> Annual International Symposium on Computer Architecture; published 2000; pages 25-36
	W	Oh et al.; "Error Detection by Duplicated Instructions in Super-Scalar Processors"; IEEE Transactions on Reliability, volume 51, number 1, March 2002; pages 63-75
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.